INTERNATIONAL SEARCH REPORT

In tional Application No PCT/GB2004/003680

A. CLASSIFICATION OF SUBJECT MATTER IPC 7 G01N23/06 G01N G01N23/223 G01N23/227 According to International Patent Classification (IPC) or to both national classification and IPC **B. FIELDS SEARCHED** Minimum documentation searched (classification system followed by classification symbols) G01N IPC 7 Documentation searched other than minimum documentation to the extent that such documents are included in the fields searched Electronic data base consulted during the International search (name of data base and, where practical, search terms used) EPO-Internal, WPI Data, INSPEC C. DOCUMENTS CONSIDERED TO BE RELEVANT Citation of document, with indication, where appropriate, of the relevant passages Relevant to claim No. Category 9 1-12,Y R.A.ROSENBERG, J.K.SIMONS, S.P.FRIGO: 14-17 "X-ray fluorescence detection of low-Z elements using a microchannel plate detector" REVIEW OF SCIENTIFIC INSTRUMENTS, vol. 63, no. 4, April 1992 (1992-04), pages 2193-2194, XP002305295 UNITED STATES the whole document Patent family members are listed in annex. Further documents are listed in the continuation of box C. Χ Special categories of cited documents: *T* later document published after the International filing date or priority date and not in conflict with the application but cited to understand the principle or theory underlying the *A* document defining the general state of the art which is not considered to be of particular relevance Invention earlier document but published on or after the international ٠E. "X" document of particular relevance; the claimed invention cannot be considered novel or cannot be considered to filing date *L* document which may throw doubts on priority claim(s) or which is cited to establish the publication date of another citation or other special reason (as specified) involve an inventive step when the document is taken alone "Y" document of particular relevance; the claimed invention cannot be considered to involve an inventive step when the document referring to an oral disclosure, use, exhibition or document is combined with one or more other such docu ments, such combination being obvious to a person skilled other means in the art. document published prior to the international filing date but *&* document member of the same patent family later than the priority date claimed Date of mailing of the international search report Date of the actual completion of the International search 30/11/2004 12 November 2004 Authorized officer Name and mailing address of the ISA European Patent Office, P.B. 5818 Patentlaan 2 NL - 2280 HV Rijswijk Tel. (+31-70) 340-2040, Tx. 31 651 epo nl, Strohmayer, B Fax: (+31-70) 340-3016

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